PATENT 8038-1062

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Takayuki SHIMAMUNE et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed March 14, 2005

Examiner

PROCESS FOR PRODUCING HIGH-PURITY SILICON AND APPARATUS

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

March 14, 2005

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

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The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

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- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
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a.		DOCUMENTS IN THE ENGLISH LANGUAGE
		The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.
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		An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).
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If The is requested	e Exa ed to	aminer has any questions concerning this IDS, he/she contact the undersigned.
		Respectfully submitted,
		YOUNG & THOMPSON
		Benoît Castel
		Benoit Castel, Reg. No. 35,041 745 South 23 rd Street Arlington, VA 22202 Telephone (703) 521-2297 Telefax (703) 685-0573 (703) 979-4709
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INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

Attorney Docket No.: 8038-1062

^{Applicant:} Takayuki SHIMAMUNE et al.

Filing Date:

March 14, 2005

Group Art Unit:

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		U.S. PATI	ENT DOCUMENTS				
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